

## ISTFATM 2007: proceedings of the 33rd international symposium for testing and failure analysis, November 4 - 8, 2007 San Jose McEnery Convention Center San Jose, California, USA

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### Abstrak

This volume features the latest research and practical data from the premier event for the microelectronics failure analysis community. The papers cover a wide range of testing and failure analysis topics of practical value to anyone working to detect, understand, and eliminate electronic device and system failures. Case histories and review papers are included, as well as guides to new and unique tools and methodologies, applications and results.